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Application/Control No.	Applicant(s)/Patent unde Reexamination	r
10/671,326	WANG ET AL.	
Examiner	Art Unit	
Nyeemah Grazier	1626	

SEARCHED			
Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
514	236.2	11/30/2005	NG
540	467	11/30/2005	NG
544	137	11/30/2005	NG

SEARCH NOT (INCLUDING SEARCH		
	DATE	EXMR
STN (HCAPLUS Online) Structural based on Amended Claims	11/29/2005	ŅG
IDS (Supplemental IDS)	11/7/2005	NG
Updated Inventor Name Search (EDAN)	11/30/2005	NG <sup>-</sup>
Classification limited w/ Text (EAST) 514/183, 375, 376; 540/467; 544/137; 548/218, 229, 232	11/30/2005	NG
Priority	11/29/2005	NG
Patentability Conference	12/1/2005	NG
Supplemental IDS	12/1/2005	NG